

	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition	Errors
1	IS&R	L1	2	("6636998").PN.	US- PGPU B; USPA T; EPO; JPO; DERW ENT; IBM_ TDB	2006/07/ 05 16:14			
2	IS&R	L2	5	((("6636998") or ("6856158") or ("6978405") or ("6182255") or ("6094735")).PN.	USPA T	2006/07/ 05 16:15			
3	BRS	L5	1851	702/117.ccls. or 327/40.ccls. or 714/719.ccls.	US- PGPU B; USPA T; EPO; JPO; DERW ENT; IBM_ TDB	2006/07/ 05 16:34			

	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition	Errors
4	BRS	L6	1160	(702/117.ccls. or 327/40.ccls. or 714/719.ccls.) and test\$3 with (device\$1 or circuit\$1 or unit\$1)	US- PGPU B; USPA T; EPO; JPO; DERW ENT; IBM_ TDB	2006/07/ 05 16:19			
5	BRS	L7	230	(702/117.ccls. or 327/40.ccls. or 714/719.ccls.) and test\$3 with (device\$1 or circuit\$1 or unit\$1) and (compar\$4 or differen\$2) with bit\$1 with (data or information)	US- PGPU B; USPA T; EPO; JPO; DERW ENT; IBM_ TDB	2006/07/ 05 16:35			

	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition	Errors
6	BRS	L8	112	(702/117.ccls. or 327/40.ccls. or 714/719.ccls.) and test\$3 with (device\$1 or circuit\$1 or unit\$1) and (compar\$4 or differen\$2) with bit\$1 with (data or information) with output\$4	US- PGPU B; USPA T; EPO; JPO; DERW ENT; IBM_ TDB	2006/07/ 05 16:35			
7	BRS	L9	53	(702/117.ccls. or 327/40.ccls. or 714/719.ccls.) and test\$3 with (device\$1 or circuit\$1 or unit\$1) same (compar\$4 or differen\$2) with bit\$1 with (data or information) with output\$4	US- PGPU B; USPA T; EPO; JPO; DERW ENT; IBM_ TDB	2006/07/ 05 16:35			

	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition	Errors
8	BRS	L10	9	(702/117.ccls. or 327/40.ccls. or 714/719.ccls.) and test\$3 with (device\$1 or circuit\$1 or unit\$1) same (compar\$4 or differen\$2) with bit\$1 with (data or information) with output\$4 and judg\$5	US- PGPU B; USPA T; EPO; JPO; DERW ENT; IBM_ TDB	2006/07/ 05 16:38			

	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition	Errors
9	BRS	L11	1	(702/117.ccls. or 327/40.ccls. or 714/719.ccls.) and block\$1 with test\$3 with (device\$1 or circuit\$1 or unit\$1) same (compar\$4 or differen\$2) with bit\$1 with (data or information) with output\$4 and judg\$5 and logical\$2 with process\$3	US- PGPU B; USPA T; EPO; JPO; DERW ENT; IBM- TDB	2006/07/ 05 16:38			

	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition	Errors
10	BRS	L12	3	(702/117.ccls. or 327/40.ccls. or 714/719.ccls.) and block\$1 with test\$3 with (device\$1 or circuit\$1 or unit\$1) and (compar\$4 or differen\$2) with bit\$1 with (data or information) with output\$4 and judg\$5 and logical\$2 with process\$3	US- PGPU B; USPA T; EPO; JPO; DERW ENT; IBM- TDB	2006/07/ 05 16:29			

	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition	Errors
11	BRS	L13	2	(702/117.ccls. or 327/40.ccls. or 714/719.ccls.) and block\$1 with test\$3 with (device\$1 or circuit\$1 or unit\$1) and (compar\$4 or differen\$2) with bit\$1 with (data or information) with (reference\$1 or predetermined or preset\$4 or predefined or expected or desired or threshold\$1) and judg\$5 and logical\$2 with process\$3	US- PGPU B; USPA T; EPO; JPO; DERW ENT; IBM_ TDB	2006/07/ 05 16:31			

	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition	Errors
12	BRS	L14	4	block\$1 with test\$3 with (device\$1 or circuit\$1 or unit\$1) and (compar\$4 or differen\$2) with bit\$1 with (data or information) with (reference\$1 or predetermined or preset\$4 or predefined or expected or desired or threshold\$1) and judg\$5 and logical\$2 with process\$3	US- PGPU B; USPA T; EPO; JPO; DERW ENT; IBM_ TDB	2006/07/ 05 16:31			

	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition	Errors
13	BRS	L15	6	(array\$1 or block\$1 or serial) with test\$3 with (device\$1 or circuit\$1 or unit\$1) and (compar\$4 or differen\$2) with bit\$1 with (data or information) with (reference\$1 or predetermined or preset\$4 or predefined or expected or desired or threshold\$1) and judg\$5 and logical\$2 with process\$3	US- PGPU B; USPA T; EPO; JPO; DERW ENT; IBM_ TDB	2006/07/ 05 16:31			

	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition	Errors
14	BRS	L16	2166	702/117.ccls. or 327/40.ccls. or 714/719.ccls. or 324/523.ccls.	US- PGPU B; USPA T; EPO; JPO; DERW ENT; IBM_ TDB	2006/07/ 05 16:37			
15	BRS	L17	230	(702/117.ccls. or 327/40.ccls. or 714/719.ccls. or 324/523.ccls.) and test\$3 with (device\$1 or circuit\$1 or unit\$1) and (compar\$4 or differen\$2) with bit\$1 with (data or information)	US- PGPU B; USPA T; EPO; JPO; DERW ENT; IBM_ TDB	2006/07/ 05 16:37			

	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition	Errors
16	BRS	L18	112	(702/117.ccls. or 327/40.ccls. or 714/719.ccls. or 324/523.ccls.) and test\$3 with (device\$1 or circuit\$1 or unit\$1) and (compar\$4 or differen\$2) with bit\$1 with (data or IBM_ information) with output\$4	US- PGPU B; USPA T; EPO; JPO; DERW ENT; IBM_ TDB	2006/07/ 05 16:37			
17	BRS	L19	53	(702/117.ccls. or 327/40.ccls. or 714/719.ccls. or 324/523.ccls.) and test\$3 with (device\$1 or circuit\$1 or unit\$1) same (compar\$4 or differen\$2) with bit\$1 with (data or IBM_ information) with output\$4	US- PGPU B; USPA T; EPO; JPO; DERW ENT; IBM_ TDB	2006/07/ 05 16:37			

	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition	Errors
18	BRS	L20	6772	702/117.ccls. or 327/40.ccls. or 714/719.ccls. or 324/523,765.ccls.	US- PGPU B; USPA T; EPO; JPO; DERW ENT; IBM_ TDB	2006/07/ 05 16:37			
19	BRS	L21	286	(702/117.ccls. or 327/40.ccls. or 714/719.ccls. or 324/765.ccls.) and test\$3 with (device\$1 or circuit\$1 or unit\$1) and (compar\$4 or differen\$2) with bit\$1 with (data or information)	US- PGPU B; USPA T; EPO; JPO; DERW ENT; IBM_ TDB	2006/07/ 05 16:37			

	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition	Errors
20	BRS	L22	134	(702/117.ccls. or 327/40.ccls. or 714/719.ccls. or 324/765.ccls.) and test\$3 with (device\$1 or circuit\$1 or unit\$1) and (compar\$4 or differen\$2) with bit\$1 with (data or information) with output\$4	US- PGPU B; USPA T; EPO; JPO; DERW ENT; IBM_ TDB	2006/07/ 05 16:37			
21	BRS	L23	60	(702/117.ccls. or 327/40.ccls. or 714/719.ccls. or 324/765.ccls.) and test\$3 with (device\$1 or circuit\$1 or unit\$1) same (compar\$4 or differen\$2) with bit\$1 with (data or information) with output\$4	US- PGPU B; USPA T; EPO; JPO; DERW ENT; IBM_ TDB	2006/07/ 05 16:38			

	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition	Errors
22	BRS	L24	9	(702/117.ccls. or 327/40.ccls. or 714/719.ccls. or 324/765.ccls.) and test\$3 with (device\$1 or circuit\$1 or unit\$1) same (compar\$4 or differen\$2) with bit\$1 with (data or information) with output\$4 and judg\$5	US- PGPU B; USPA T; EPO; JPO; DERW ENT; IBM_ TDB	2006/07/ 05 16:38			

	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition	Errors
23	BRS	L25	1	(702/117.ccls. or 327/40.ccls. or 714/719.ccls. or 324/765.ccls.) and block\$1 with test\$3 with (device\$1 or circuit\$1 or unit\$1) same (compar\$4 or differen\$2) with bit\$1 with (data or information) with output\$4 and judg\$5 and logical\$2 with process\$3	US- PGPU B; USPA T; EPO; JPO; DERW ENT; IBM_ TDB	2006/07/ 05 16:38			

	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition	Errors
24	BRS	L26	9	(702/117.ccls. or 327/40.ccls. or 714/719.ccls. or 324/765.ccls.) and test\$3 with (device\$1 or circuit\$1 or unit\$1) same (compar\$4 or differen\$2) with bit\$1 with (data or information) with output\$4	US- PGPU B	2006/07/ 05 16:39			

	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition	Errors
25	BRS	L27	12	(702/117.ccls. or 327/40.ccls. or 714/719.ccls. or 324/765.ccls.) and (array\$1 or block\$1 or serial) with test\$3 with (device\$1 or circuit\$1 or unit\$1) and (compar\$4 or differen\$2) with bit\$1 with (data or information) with (reference\$1 or predetermined or preset\$4 or predefined or expected or desired or threshold\$1)	US- PGPU B	2006/07/ 05 16:39			

	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition	Errors
26	BRS	L28	1	(array\$1 or block\$1 or serial) with test\$3 with (device\$1 or circuit\$1 or unit\$1) and (compar\$4 or differen\$2) with bit\$1 with (data or information) with (reference\$1 or predetermined or preset\$4 or predefined or expected or desired or threshold\$1) and judg\$5 and logical\$2 with process\$3 and non-volatile with memory	US-PGPU B; USPA T; EPO; JPO; DERW ENT; IBM_TDB	2006/07/05 16:47			

	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition	Errors
27	BRS	L29	8	(array\$1 or block\$1 or serial) with test\$3 with (device\$1 or circuit\$1 or unit\$1) and (compar\$4 or differen\$2) with bit\$1 with (data or information) with (reference\$1 or predetermined or preset\$4 or predefined or expected or desired or threshold\$1) and logical\$2 with process\$3 and non-volatile with memory	US-PGPU B; USPA T; EPO; JPO; DERW ENT; IBM-TDB	2006/07/05 16:49			

	Type	L #	Hits	Search Text	DBs	Time Stamp	Comments	Error Definition	Errors
28	BRS	L30	1	(array\$1 or block\$1 or serial) with test\$3 with (device\$1 or circuit\$1 or unit\$1) and (compar\$4 or differen\$2) with bit\$1 with (data or information) with (reference\$1 or predetermined or preset\$4 or predefined or expected or desired or threshold\$1) and logical\$2 with process\$3 and non-volatile with memory and judge\$5	US-PGPU B; USPA T; EPO; JPO; DERW ENT; IBM-TDB	2006/07/05 16:50			

	U	1	Document ID	Issue Date	Pages	Title	Current OR	Current XRef	Retrieval Classif
1			US 2006006426 5 A1	20060323	16	System and method for burn-in test control	702/117		702/117
2	X		US 2006004746 3 A1	20060302	17	Bit synchronization for high-speed serial device testing	702/120	702/117	702/117
3	X		US 2005011406 3 A1	20050526	34	Semiconductor device and testing circuit which can carry out a verifying test effectively for non-volatile memory cells	702/117		702/117
4	X		US 2004004658 6 A1	20040311		Semiconductor integrated circuit	324/765		324/765
5	X		US 2003021731 3 A1	20031120		Method and auxiliary device for testing a RAM memory circuit	714/719		714/719

	U	1	Document ID	Issue Date	Pages	Title	Current OR	Current XRef	Retrieval Classif
6	X		US 2003020178 8 A1	20031030		Reference voltage generating device, semiconductor integrated circuit including the same, and testing device and method for semiconductor integrated circuit	324/765		324/765
7	X		US 2003018433 5 A1	20031002		Method of electrically testing semiconductor devices	324/765		324/765
8	X		US 2003001139 6 A1	20030116		Semiconductor device and test system therefor	324/765		324/765
9	X		US 2002012930 8 A1	20020912		Multi-bit test circuit	714/719		714/719
10	X		US 2002003253 7 A1	20020314		Method and system for testing RAMBUS memory modules	702/117		702/117
11	X		US 2002002912 3 A1	20020307		Semiconductor device and semiconductor device testing method	702/117		702/117

	U	1	Document ID	Issue Date	Page s	Title	Current OR	Current XRef	Retrieval Classif
12	X		US 2001004223 1 A1	20011115		Memory testing apparatus and method	714/719		714/719